Summary

- ▼ Hypothesis testing
 - ▼ testing statistical hypothesis
 - ▼ Setup

Let $X\sim F$ be a r.v. with $F\in \mathcal{F}$ unknown (\mathcal{F} space of all possible cdfs) . Then we define two sets $H_0,H_1\subset \mathcal{F}$ and test if:

$$F \in H_0 \text{ or } F \in H_1$$

Hypothesis (H_0, H_1) could be

- simple
 - $\circ |H_0|=1$
- · composite

$$\circ |H_0| > 1$$

▼ Range

The distributions in H_0 and H_1 imply a **range** of outcomes $R(H_0), R(H_1)$. The range is all possible outcomes under the distributions of H_1 and H_0 .

▼ Critical region

A **critical region** is a set of outcomes C_r such that iff $x \in C_r$ we reject H_0 .

The acceptance region is the compliment of the critical region ${\cal C}_a={\cal C}_r^c$.

We therefore partitioning the sample space into two sets

▼ test statistic

Sometimes it is hard to find C_r for a given signficance level α (more on this in type one and type two error section) We therefore look at the **test-statistic**

Let $t:\mathbb{R}^k o\mathbb{R}$. Then we call the test stastitic $t(\overset{
ightarrow}{X})$ and $C_r=\{x:t(x)\in C_r^T\}$.

▼ type one and type two error

The type one error is the false rejection of H_0 :

$$lpha = P(ext{type one error}) = P(X \in C_r | F \in H_0)$$

The type two error is the false acceptance of H_0 :

$$eta = P(ext{type two error}) = P(X \in C_a | F \in H_1)$$

	Tı	True probability distribution	
		H is true	H is not true
Test decision	Rejection of H	Type I Error	correct decision
	Acceptance of H	correct decision	Type II Error

▼ properties

▼ Parametric vs non-parametric

Parametric: $H_0 = \{f(x; heta) | heta \in \Theta\}$ characterized by a set of parameters

Non-parametric: everything else

- ▼ power function
 - ▼ Parametric definition

The powerfunction is given by the probability that an outcome in C_r is realized:

$$\pi(heta) = P(X \in C_r | heta)$$

If $f(x;\theta) \in H_0$ then $\pi(\theta) = P(\text{type one error})$ and if $f(x;\theta) \in H_1$ we can say $\pi(\theta) = P(\text{correct decision})$.

The ideal power function is:

$$\pi_o(heta) = egin{cases} 1 ext{ if } f(x; heta) \in H_1 \ 0 ext{ else} \end{cases}$$

▼ Inadmissability

A set C_r is **inadmissable iff** there exists an alternative critical region C_r^* such that the power-function of this alternative is better than the on by C_r .

We than say, that the test with C_r is **dominated** by C_r^* .

▼ Size of a test

We call the size α of a test:

$$lpha = \sup_{ heta \in H_0} \pi(heta) = \sup_{ heta \in H_0} P(X \in C_r | heta)$$

▼ Uniformly most powerful tests

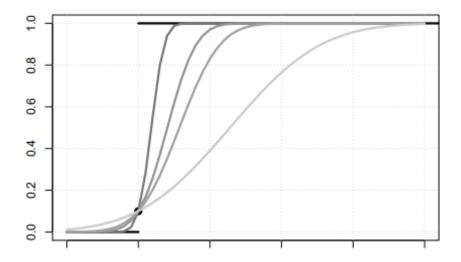
Basically the best C_r possible.

▼ Consistency

Let C_{rn} be the critical region induced by the sample $(X_1,...,X_n)$. Let the significance level be fixed at $\alpha>0$. Then the test is called **consistent** iff:

$$\pi_{C_{rn}}(heta) \longrightarrow 1 \quad orall heta \in H_1$$

Plotting the sequence of induced power-functions could look smth like:



- ▼ asymptotic distributions
- ▼ test statistics
 - ▼ Likelihood ratio

We want to compare, how likely $\theta \in H_0$ is compared to $\theta \in H_0 \cup H_1$. Therefore we construct the test statistic:

$$\lambda(x) = rac{\displaystyle \sup_{ heta \in H_0} \mathcal{L}(heta;x)}{\displaystyle \sup_{ heta \in H_0 \cup H_1} \mathcal{L}(heta;x)}$$

Where $\mathcal L$ is the generalized Likelyhood function. The critical region is defined by a $c\in\mathbb R$ where the test rejects H_0 iff $\lambda(x)\leq c$.

▼ asymptotic null distribution

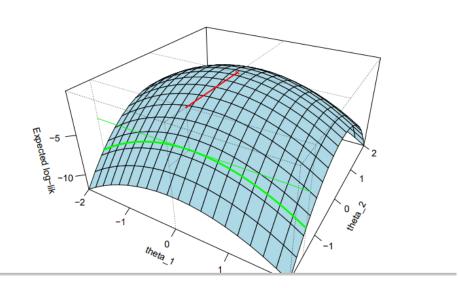
If we have a restriction of $H_0:R(\theta)=R$ and $H_1:R(\theta)\neq R$. Where $R(\theta)$ is a smooth q-dimensional vector function, then under H_0 it holds that:

$$-2\log\lambda(X)\stackrel{d}{\longrightarrow}\mathcal{X}_q^2$$

▼ Wald

This test looks at the distance between the restricted and unrestricted estimate.

Wald's idea



This is basically a t-test. This is why it is not further discussed in the lecture.

Lagrange multiplier (or score test)

Looks at the gradient of the restricted maximum of the log likelyhood.

Looking at the restricted maximization problem:

$$\max_{\theta,\lambda} \{ \ln \mathcal{L}(\theta; x) - \lambda' [R(\theta) - R] \}$$

If the restriction $R(\theta)-R$ is binding, the λ' should be non zero. So only if the restriction is keeping you away from the maximum, you get Lagrange coefficients not equal to zero

- ▼ what if the restricted maximum is a local maximum?
 This why we look at different tests for log likelyhoodss
- ▼ multiple testing
- ▼ Confidence Intervalls
 - ▼ basic setup

Let there be a "data dependent interval $[t_1(X),t_2(X)]$ such that $P(\theta \in [t_1(X),t_2(X)])$ becomes maximal and $t_2(X)-t_1(X)$ becomes minimal.

We can generalize this idea to confidence sets C(X). So choose C(X) such that $P(\theta \in C(X))$ (this metric is called the **coverage probability**) becomes maximal and the volume of C(X) becomes minimal

▼ confidence level

The confidence level is the smallest possible coverage probability:

$$CL_C = \inf_{ heta \in \Theta} P_{ heta}(heta \in C(X))$$

▼ Pivotal variables

Choose a transformation $T(X_1,...,X_n,\theta)$, that is not dependent on θ . Then do the following steps:

- 1. Find $a,b\in\mathbb{R}$ such that: $P(a\leq T\leq b)=1-lpha$ for all $\theta\in\Theta$.
- 2. "Invert" T such that $\theta = t^*(X,T)$.

3. Construct C(X) with $t^*(X,a)$ and $t^*(X,b)$.

We covered an example with the empirical variance with iid sample $(X_1,...,X_n)$ with $X_i \overset{iid}{\sim} \mathcal{N}(\mu,\sigma^2)$. Then it holds that:

$$S_n^2 := rac{1}{n} \sum_{i=1}^n (X_i - ar{X}_n)^2 \implies n S_n^2/\sigma^2 \sim \mathcal{X}_{n-1}^2$$

But then it holds that:

$$P\left(rac{nS_n^2}{\mathcal{X}_{n-1;lpha}^2} \leq \sigma^2 \leq rac{nS_n^2}{\mathcal{X}_{n-1;1-lpha}^2}
ight) = 1-lpha$$

But because this is the confidence level, we at the same time form a critical region for a test of size α with the compliment of this interval.

▼ Basics of decision theory

▼ Decision space

Set of possible decisions D.

If $D=\Omega$ then we are looking at the forecast.

If $D=\Theta$ we are looking at (point) estimation

▼ Loss function

Let $X=(X_1,...,X_d)$ be a random vector with $X\sim F(x|\theta)$ a parametric cdf.

We call the function $L:\Theta\times D\to\mathbb{R}$ a loss function. We would like to chose $d\in D$ such that: $L(\theta,d)$ gets minimal.

▼ Utility function

If we have benifits, that arise from our choice of $d\in D$ we can capture them in a **utility-function** $U:\Theta\times D\to\mathbb{R}$.

Then choose d such that:

$$\min_{d} U(\theta, d)$$

▼ Risk

Let $L:\Theta\times D\to\mathbb{R}$ be a loss function. And $\delta(x)$ be a deterministic decision rule. Then the **risk** is defined by:

$$R(\theta, \delta(x)) = \mathbb{E}(L(\theta, \delta(X)))$$

The expected loss

▼ Examples

Solutions for loss functions:

$$L(heta,d) = (heta-d)^2 \implies d(x) = \mathbb{E}(heta|x) \ L(heta,d) = | heta-d| \implies d(x) = m(x| heta)$$

▼ Optimization techniques

▼ Bayes

We can give a prior distribution of $\theta \in \Theta$. The Bayes-risk is then defined by:

$$B(\pi,\delta) = \int R(heta,\delta)\pi(heta)d heta$$

The Bayes-decision rule is now the one with the lowest Bayes-Risk:

$$B(\pi,\delta_B) = rg \min_{\delta \in D} B(\pi,\delta)$$

▼ non informative prior

If you have no information on the prior, every θ is equally likely:

$$\pi(heta) = c \in \mathbb{R} \quad orall heta \in \Theta$$

▼ Non-randomized Bayes

There is no randomized prior, that improves over a non-randomized prior. So all Bayes-Risks are based on non-random priors.

Admissibility

If continuity on Θ for the prior $\pi(\theta)$ is given and the support $\mathcal{S}_{\pi}=\Theta$ is the whole parameter space, the resulting rule δ_B is admissible

▼ Shape of risk-points

The set of admissible decisions $\delta \in \mathcal{D}$ have risk-points \mathcal{R} with \mathbf{convex} shape

▼ positive Bayes-rule

If Θ is finite with $|\Theta|=k$ and $\pi(\theta)>0 \forall \theta\in\Theta$. Then the resulting rule δ_B is called **positive Bayes-Rule**

Every positive Bayes-Rule is positive

▼ MiniMax

▼ Definition with Bayes-Risk

Let Θ^* be the set of all prior distributions then the minimax rule δ_M is:

$$\sup_{\pi \in \Theta^*} B(\pi, \delta_M) = \inf_{\delta \in \mathcal{D}} \sup_{\pi \in \Theta^*} B(\pi, \delta)$$

While \mathcal{D} is a class of decisions.

We call this the upper value $ar{V}$:

$$ar{V} := \inf_{\delta \in \mathcal{D}} \sup_{\pi \in \mathbf{\Theta}^*} B(\pi, \delta)$$

The lower value \underline{V} is:

$$\underline{\mathrm{V}} := \sup_{\pi \in \Theta^*} \inf_{\delta \in \mathcal{D}} B(\pi, \delta)$$

It comes natural that a given rule δ_M is a minimax rule iff:

$$\sup_{\pi\in\Theta^*}B(\pi,\delta_M)=ar{V}$$

▼ least favourable distribution

The least favourable distribution τ_0 is a l.f.d. iff:

$$\inf_{\delta \in \mathcal{D}} B(au_0, \delta) = \operatorname{\overline{V}}$$

▼ value of the game

If $\underline{V} = \bar{V} = V$ then V is called the value of the game.

Also the minimax rule

▼ How to find the least favourable distribution

Some times boundary priors are least favourable, because the risk increases at the boundaries. Sometimes there exists a sequence of constants c_m and of priors $\pi_m(\theta)$ such that:

$$c_m\pi_m(heta) \mathop{\longrightarrow}\limits_{n o\infty} au_0(heta)$$

▼ Another way of defining a minimax rule

A minimax rule δ_0 fulfills the property, with π_m being an approximation of the least favourable rule. :

$$R(heta,\delta_0) \leq \lim_{m o\infty} B(\pi_m,\delta_m) \quad orall heta \in \Theta$$

This means, regardless of the parameter θ , the risk is always lower than baysian with the worst prior.

▼ Equalizer Rules

An equalizer rule $\delta \in D$ yields a constant risk over all $\theta \in \Theta$:

$$R(heta,\delta)=c\in\mathbb{R}\quad orall heta\in\Theta$$

Every admissible equalizer rule is also a minimax rule.

▼ Example

Let $X_i \overset{iid}{\sim} \mathcal{N}(\theta,\sigma^2)$ with $L(\theta,d)=(d-\theta)^2$. Then $d=\bar{X}$ is an equalizer rule for n=1:

$$egin{aligned} R(heta,ar{X}) &= \mathbb{E}((ar{X}- heta)^2) \ &= Var(ar{X}) \ &= \sigma^2/n \ &= \sigma^2 \end{aligned}$$

So regardless of the prior $\pi(\theta)$ the Bayes-risk is always σ^2 .

▼ Shrinkage methods

We have seen that d=X is a valid minimax rule for $X\sim \mathcal{N}(\theta,\sigma^2)$. But what about the multidimensional case?

If we have $X \sim \mathcal{N}(\theta, I_p)$ does this still hold?

In that case we would get:

$$R(\theta, X) = p$$

But for p > 2 we get an **R-better** rule by way of **shrinkage**.

This **James Stein** estimator shrinks the estimation:

$$\delta_{JS} = X \left(1 - rac{p-2}{\|X\|^2}
ight)$$

It turns out that:

$$R(heta,\delta_{JS}) = p - (p-2)^2 \mathbb{E}\left(rac{1}{\|X\|^2}
ight) < \mathbb{E}(heta,X)$$

With shrinkage, we introduce a bias and reduce the variance. But the reduction in variance is always be greater than the increase in bias.

▼ Optimal shrinkage estimator

The optimal shrinkage b^* requires knowledge of $\|\theta\|$. We can estimate $\|\theta\|$ by $\|X\|^2-p$. But this would lead to a bias in the estimator. There is nothing on $R(\theta,b^*X)$

If we have a more general setup like $X \sim \mathcal{N}(\theta, \Sigma)$ we can use:

$$\delta_{JS} = \left(1 - rac{ ilde{p} - 2}{X' \Sigma^{-1} X}
ight)$$

With $ilde p=tr(\Sigma)/\lambda_{max}(\Sigma)$ with λ_{max} being the largest eigenvalue of Σ .

Why an estimation-problem with one observation?

Consider this linear regression problem:

$$Y = Xeta + \epsilon \quad \epsilon \sim \mathcal{N}(0, \sigma^2), X \in \mathbb{R}^n$$

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Then it holds that:

$$Y \sim \mathcal{N}(Xeta, \sigma^2 I_n)$$

Now we don't know β . Let's estimate it using OLS:

$$\hat{\beta} = (X'X)^{-1}X'Y$$

Since X is deterministic, we are looking at a **deterministic and** linear transformation of Y and therefore know the distribution of $\hat{\beta}$:

$$\hat{eta} \sim \mathcal{N}(eta, \sigma^2(X'X)^{-1})$$

But get this: $X\hat{\beta} = X(X'X)^{-1}X'Y$ so we know the distribution of that too:

$$X\hat{eta} \sim \mathcal{N}(Xeta, \sigma^2 X (X'X)^{-1} X')$$

We are now looking at the same problem stated above. We have one realization of $X\hat{\beta}$ and are interested in $\theta=X\beta$. We therefore know that $X\hat{\beta}$ is NOT an admissible decision rule for $X\beta$. We can now apply shrinkage and get an better estimation of $X\beta$. The James Stein estimator is now:

$$\delta_{JS} = \left(1 - rac{(p-2)\sigma^2}{\hat{eta}'(X'X)\hat{eta}}
ight)X\hat{eta}$$

▼ Hypothesis Testing

▼ randomized decisions

Consider the set up of $\Theta = \{\theta_1, \theta_2\}$ and $D = \{d_0, d_1\}$ (classic test setup) then we can randomize the decision rule by:

$$\delta(x) = (1 - \phi(x), \phi(x))$$

Where simply:

$$\phi(x) = P(\delta = d_1 | X = x)$$

Under $L(heta,\delta)=1_{\{\delta
eq heta\}}$ we have:

$$egin{aligned} R(heta_0,\delta) &= P_{ heta_0}(\delta(x) = d_1) \ R(heta_1,\delta) &= P_{ heta_1}(\delta(x) = d_0) \end{aligned}$$

▼ size and power of the test

We can say that:

$$lpha(\phi) = P_{ heta_0}(\delta(X) = d_1) = R(heta_0, \delta) \ eta(\phi) = P_{ heta_1}(\delta(X) = d_1) = 1 - R(heta_1, \delta)$$

This gives us the risk points:

$$egin{aligned} \mathcal{R} &= \{R(heta_0, \delta), R(heta_1, \delta), orall \delta \in \mathcal{D}\} \ &= \{lpha(\phi), 1 - eta(\phi), orall \phi \in \mathcal{D}\} \end{aligned}$$

▼ uniformly most powerful test

The best test of level α_0 minimizes the type II error while keeping the probability of a type I error under α_0 .

$$\mathbb{E}_{\theta_0}(\phi(X)) = \alpha(\phi) \le \alpha_0 \tag{1}$$

$$\mathbb{E}_{\theta_1}(1 - \phi(X)) \le \mathbb{E}_{\theta_1}(1 - \phi'(X)) \forall \phi' \text{ satisfying (1)}$$
 (2)

▼ Neyman-Pearson Lemma

Consider the previous set up and the corresponding densities $f(x|\theta_0)=f_0(x)$ and $f(x|\theta_1)=f_1(x)$. With:

$$f_i:\mathbb{R}^n o\mathbb{R}\quad i\in\{0,1\}$$

We consider the tests with the mapping $\phi(x)$ of the form:

$$\phi(x) = egin{cases} 1 & f_1(x) > k f_0(x) \ \gamma(x) & f_1(x) = k f_0(x) \ 0 & f_1(x) < k f_0(x) \end{cases}$$

With
$$\gamma:\mathbb{R}^n o [0,1]$$
 and $k\in [0,\infty].$

The Neyman-Pearson Lemma states, there exists a most powerful test in this class for every level α_0 .

▼ Uniformly most powerful onesided testing

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